



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re the Application of

Inventors: Osamu ICHIKAWA

Art Unit: 2829

Appln. No.: 10/647,506

Exr.: J. Hollington

Filed: August 26, 2003

For: SEMICONDUCTOR INTEGRATED CIRCUIT AND MEMORY TEST  
METHOD

PRELIMINARY AMENDMENT

Honorable Commissioner of  
Patents and Trademarks  
Washington, DC 20231

Sir:

Please amend the above application as follows:

02/02/2005 FFANAEIA 00000084 10647506

01 FC:1201  
02 FC:1202

400.00 OP  
100.00 OP